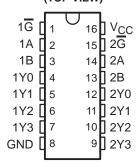
- EPIC[™] (Enhanced-Performance Implanted CMOS) Process
- Designed Specifically for High-Speed Memory Decoders and Data-Transmission Systems
- Incorporate Two Enable Inputs to Simplify Cascading and/or Data Reception
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Small-Outline (D, NS), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), and Thin Shrink Small-Outline (PW) Packages, Ceramic Flat (W) Packages, Chip Carriers (FK), and DIPs (J)

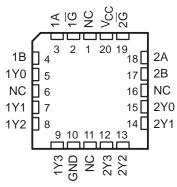
description

The 'LV139A devices are dual 2-line to 4-line decoders/demultiplexers designed for 2-V to 5.5-V V_{CC} operation.

These devices are designed for high-performance memory-decoding or data-routing applications requiring very short propagation delay times. In high-performance memory systems, these SN54LV139A . . . J OR W PACKAGE SN74LV139A . . . D, DB, DGV, NS, OR PW PACKAGE (TOP VIEW)



SN54LV139A . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

decoders can minimize the effects of system decoding. When employed with high-speed memories utilizing a fast enable circuit, the delay time of these decoders and the enable time of the memory are usually less than the typical access time of the memory. This means that the effective system delay introduced by the decoders is negligible.

The 'LV139A devices comprise two individual 2-line to 4-line decoders in a single package. The active-low enable (\overline{G}) input can be used as a data line in demultiplexing applications. These decoders/demultiplexers feature fully buffered inputs, each of which represents only one normalized load to its driving circuit.

The SN54LV139A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74LV139A is characterized for operation from –40°C to 85°C.



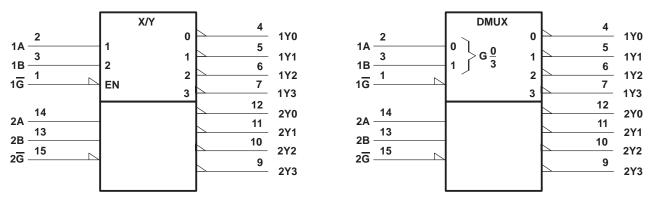
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



FUNCTION TABLE

	INPUTS			OUT	PUTS	
_ SELECT						
G	В	Α	Y0	Y1	Y2	Y3
Н	Х	Χ	Н	Н	Н	Н
L	L	L	L	Н	Н	Н
L	L	Н	Н	L	Н	Н
L	Н	L	Н	Н	L	Н
L	Н	Н	Н	Н	Н	L

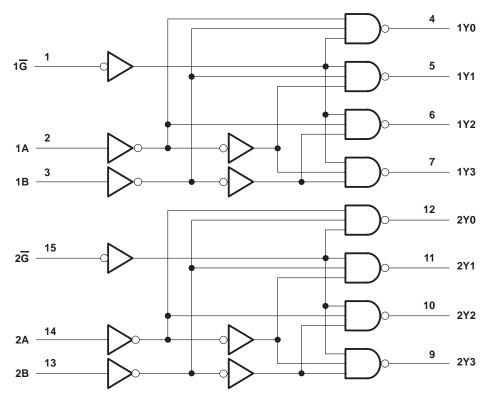
logic symbols (alternatives)†



[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, DGV, J, NS, PW, and W packages.



logic diagram (positive logic)



Pin numbers shown are for the D, DB, DGV, J, NS, PW, and W packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}		–0.5 V to 7 V
Input voltage range, V _I (see Note 1)		–0.5 V to 7 V
Output voltage range, V _O (see Notes 1 and 2)		–0.5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$)		–20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CO}	c)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	- 	±25 mA
Continuous current through V _{CC} or GND		±50 mA
Package thermal impedance, θ _{JA} (see Note 3):	: D package	113°C/W
	DB package	131°C/W
	DGV package	180°C/W
	NS package	
	PW package	149°C/W
Storage temperature range, T _{stg}		–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. This value is limited to 7 V maximum.
 - 3. The package thermal impedance is calculated in accordance with JESD 51.



recommended operating conditions (see Note 4)

			SN54L\	SN54LV139A		SN74LV139A	
			MIN MAX MIN MAX				UNIT
Vcc	Supply voltage		2	5.5	2	5.5	V
		V _{CC} = 2 V	1.5		1.5		
\/	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	V _{CC} ×0.7		V _{CC} ×0.7	7	V
VIH	nigri-iever iriput voitage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	V _{CC} ×0.7		$V_{CC} \times 0.7$	7	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	V _{CC} ×0.7		$V_{CC} \times 0.7$	7	
		V _{CC} = 2 V		0.5		0.5	
V_{IL}	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	V	CC × 0.3	,	√CC×0.3	V
۷IL	Low-level input voltage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	V	V _{CC} × 0.3		V _{CC} × 0.3	
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	V	V _{CC} ×0.3		V _{CC} × 0.3	
٧ _I	Input voltage		0	5.5	0	5.5	V
٧o	Output voltage		0 4	V _{CC}	0	VCC	V
		V _{CC} = 2 V	3	-50		-50	μΑ
lou	High-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	20	-2		-2	
ЮН	riigh-level output current	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	d _Q	-6		-6	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		-12		-12	
		V _{CC} = 2 V		50		50	μΑ
lo	Low-level output current	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		2		2	
IOL	Low-level output current	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		6		6	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		12		12	
		$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0	200	0	200	
$\Delta t/\Delta v$	Input transition rise or fall rate	$V_{CC} = 3 V \text{ to } 3.6 V$	0	100	0	100	ns/V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	0	20	0	20	
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		SN54LV139A	SN74LV139A	UNIT
PARAMETER	TEST CONDITIONS	v _{CC}	MIN TYP MAX	MIN TYP MAX	UNII
	I _{OH} = -50 μA	2 V to 5.5 V	V _{CC} -0.1	V _{CC} -0.1	
Va.,	I _{OH} = -2 mA	2.3 V	2	2	V
VOH	I _{OH} = -6 mA	3 V	2.48	2.48	V
	I _{OH} = -12 mA	4.5 V	3.8	3.8	
	$I_{OL} = 50 \mu A$	2 V to 5.5 V	0.1	0.1	
V _{OL}	I _{OL} = 2 mA	2.3 V	0.4	0.4	V
VOL.	I _{OL} = 6 mA	3 V	0.44	0.44	V
	I _{OL} = 12 mA	4.5 V	0.55	0.55	
lį	V _I = V _{CC} or GND	5.5 V	±1	±1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V	20	20	μΑ
l _{off}	V_I or $V_O = 0$ to 5.5 V	0 V	5	5	μΑ
Ci	V _I = V _{CC} or GND	3.3 V	1.9	1.9	pF

switching characteristics over recommended operating free-air temperature range, V_{CC} = 2.5 V \pm 0.2 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	LOAD T _A = 25°C		SN54LV139A		SN74LV139A		UNIT	
	(INPUT) (OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	ONIT	
^t pd*	A or B	Υ	C _L = 15 pF		7.7	17.6	1	21	1	21	ns
	G	Υ			7.4	15.8	40	19	1	19	
t _{pd}	A or B	Υ	0: 50.55		10.2	22.5	1	26.5	1	26.5	no
	G	Y	C _L = 50 pF		9.9	20.2	1	24	1	24	ns

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	ղ = 25°C	;	SN54L\	/139A	SN74L\	/139A	UNIT	
Ľ	PARAIVIETER	(INPUT)	(OUTPUT) C	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
Г	4 .*	A or B	Υ	C: 45 pF		5.3	11	1	13	1	13	ne
^t pd*	G	Υ	C _L = 15 pF		5.1	9.2	. 30	11	1	11	ns	
Г	t _{pd}	A or B	Υ	C _L = 50 pF		7.3	14.5	1	16.5	1	16.5	
		G	Υ			7	12.7	1	14.5	1	14.5	ns

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

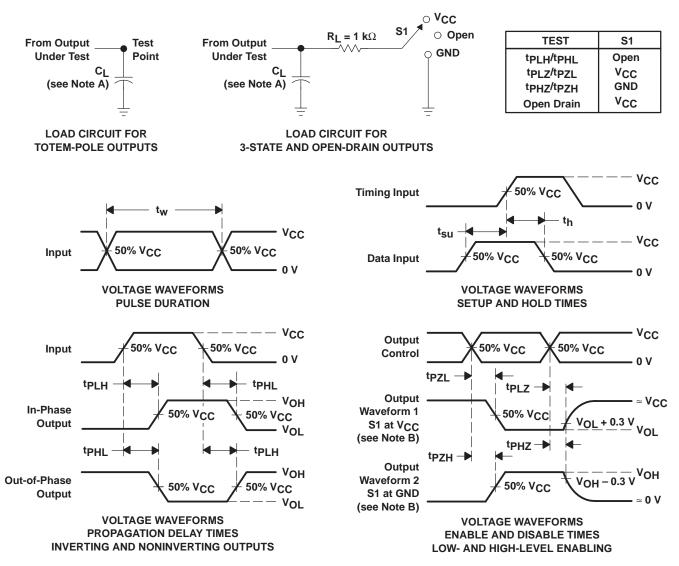
	_										
PARAMETER	FROM	то	LOAD		T _A = 25°C		SN54LV139A		SN74LV139A		UNIT
	(INPUT) (C	(OUTPUT) CAPACITANC	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
4 .*	A or B	Υ	C _L = 15 pF		3.7	7.2	1	8.5	1	8.5	20
^t pd*	G	Y			3.5	6.3	40	7.5	1	7.5	ns
^t pd	A or B	Υ	0. 50.55		5.2	9.2	1	10.5	1	10.5	20
	G	Y	C _L = 50 pF		4.9	8.3	1	9.5	1	9.5	ns

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested.

operating characteristics, T_A = 25°C

	PARAMETER	TEST CONDITIONS	VCC	TYP	UNIT
C _{pd}	Power dissination consolitance	C ₁ = 50 pF. f = 10 MHz	3.3 V	17.3	nE
	Power dissipation capacitance	$C_L = 50 \text{ pF}, f = 10 \text{ MHz}$	5 V	18.2	pF

PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_Q = 50 \Omega$, $t_f \leq 3$ ns, $t_f \leq 3$ ns.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. tpLz and tpHz are the same as tdis.
 - F. tpzL and tpzH are the same as ten.
 - G. tpHL and tpLH are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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